



T405Q-600B-TR & T405Q-600H

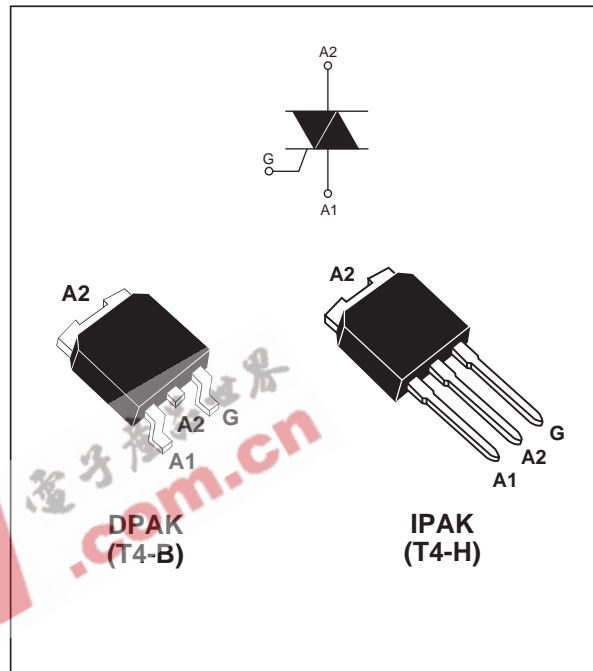
Sensitive 4Q 4A TRIAC

MAIN FEATURES

| Symbol | Value | Unit |
|-------------------|-------|------|
| $I_{T(RMS)}$ | 4 | A |
| V_{DRM}/V_{RRM} | 600 | V |
| I_{GT} | 5 | mA |

DESCRIPTION

The T405Q-600B-TR and the T405Q-600H 4 quadrants sensitive TRIACs are intended in general purpose applications where high surge current capability is required, such as irrigation systems. These TRIACs feature a gate current capability sensitivities of 5mA.



ABSOLUTE MAXIMUM RATINGS

| Symbol | Parameter | | Value | Unit |
|--------------------|--|--|--------------------------------|------------------------|
| $I_{T(RMS)}$ | RMS on-state current (Full sine wave) | DPAK / IPAK $T_c = 110^\circ\text{C}$ | 4 | A |
| I_{TSM} | Non repetitive surge peak on-state current (Full cycle, T_j initial = 25°C) | $F = 50\text{Hz}$ $t = 20\text{ms}$ | 35 | A |
| | | $F = 60\text{Hz}$ $t = 16.7\text{ms}$ | 38 | |
| I^2t | I^2t Value for fusing | $t_p = 10\text{ms}$ | 6 | A^2s |
| di/dt | Critical rate of rise of on-state current $I_G = 2 \times I_{GT}$, $t_r \leq 100\text{ns}$ | Repetitive $F = 100\text{Hz}$ | 50 | $\text{A}/\mu\text{s}$ |
| I_{GM} | Peak gate current | $t_p = 20\mu\text{s}$ $T_j = 125^\circ\text{C}$ | 4 | A |
| $P_{G(AV)}$ | Average gate power dissipation | $T_j = 125^\circ\text{C}$ | 0.5 | W |
| T_{stg} T_j | Storage junction temperature range Operating junction temperature range | | - 40 to + 150 - 40 to + 125 | $^\circ\text{C}$ |

T405Q-600B-TR & T405Q-600H

ELECTRICAL CHARACTERISTICS (T_j = 25°C, unless otherwise specified)

| Symbol | Test Conditions | Quadrant | | T405Q | Unit |
|-------------------------------------|---|--------------------|------|----------|------|
| I _{GT} ⁽¹⁾ | V _D =12V R _L =30Ω | I-II-III IV | MAX. | 5 10 | mA |
| V _{GT} | | ALL | MAX. | 1.3 | V |
| V _{GD} | V _D =V _{DRM} R _L =3.3kΩ T _j = 125°C | ALL | MIN. | 0.2 | V |
| I _H ⁽²⁾ | I _T = 100mA | | MAX. | 10 | mA |
| I _L | I _G = 1.2I _{GT} | I - III - IV II | MAX. | 10 15 | mA |
| dV/dt ⁽²⁾ | V _D =67% V _{DRM} Gate open T _j = 125°C | | MIN. | 10 | V/μs |
| (dV/dt) _c ⁽²⁾ | (dI/dt) _c = 1.8 A/ms T _j = 125°C | | MIN. | 2 | V/μs |

STATIC CHARACTERISTICS

| Symbol | Test Conditions | | | Value | Unit |
|--------------------------------------|-------------------------------------|---|------|--------|----------|
| V _{TM} ⁽²⁾ | I _{TM} = 5 A tp = 380μs | T _j = 25°C | MAX. | 1.5 | V |
| V _{TO} ⁽²⁾ | Threshold voltage | T _j = 125°C | MAX. | 0.85 | V |
| R _d ⁽²⁾ | Dynamic resistance | T _j = 125°C | MAX. | 100 | mΩ |
| I _{DRM} I _{RRM} | V _{DRM} = V _{RRM} | T _j = 25°C T _j = 125°C | MAX | 5 1 | μA mA |

Note 1: Minimum IGT is guaranteed at 5% of IGT max.

Note 2: For both polarities of A2 referenced to A1.

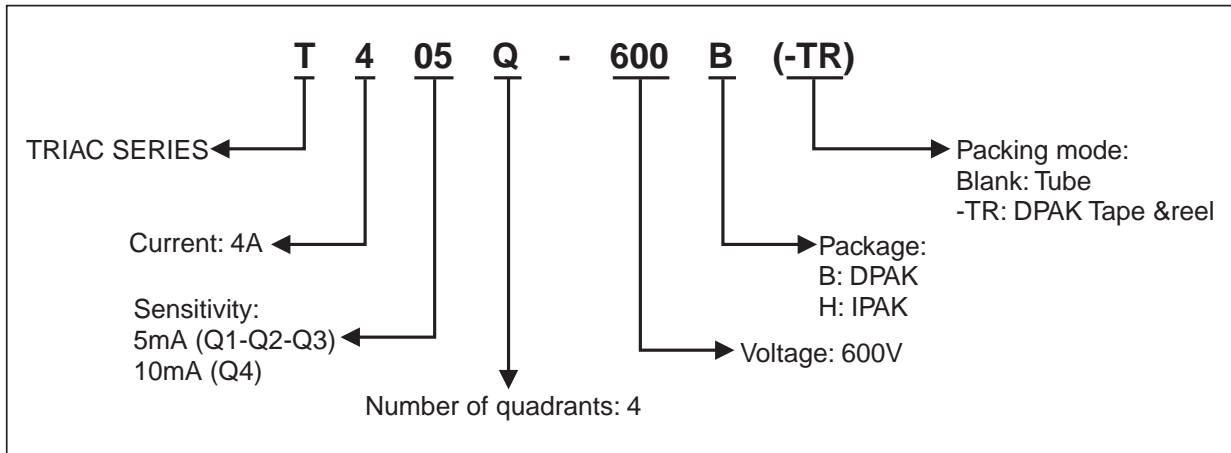
THERMAL RESISTANCES

| Symbol | Parameter | | | Value | Unit |
|----------------------|-----------------------|-------------------------|------|-------|------|
| R _{th(j-c)} | Junction to case (AC) | | | 3 | °C/W |
| R _{th(j-a)} | Junction to ambient | S = 0.5 cm ² | DPAK | 70 | °C/W |
| | | | IPAK | 100 | |

PRODUCT SELECTOR

| Part Number | Voltage | Sensitivity | Type | Package |
|---------------|---------|-------------|-----------|---------|
| T405Q-600B-TR | 600V | 5 mA | Sensitive | DPAK |
| T405Q-600H | 600V | 5 mA | Sensitive | IPAK |

ORDERING INFORMATION



OTHER INFORMATION

| Part Number | Marking | Weight | Base quantity | Packing mode |
|---------------|----------|--------|---------------|--------------|
| T405Q-600B-TR | T405Q600 | 0.3 g | 2500 | Tape & reel |
| T405Q-600H | T405Q600 | 0.4 g | 75 | Tube |

Fig. 1: Maximum power dissipation versus RMS on-state current.

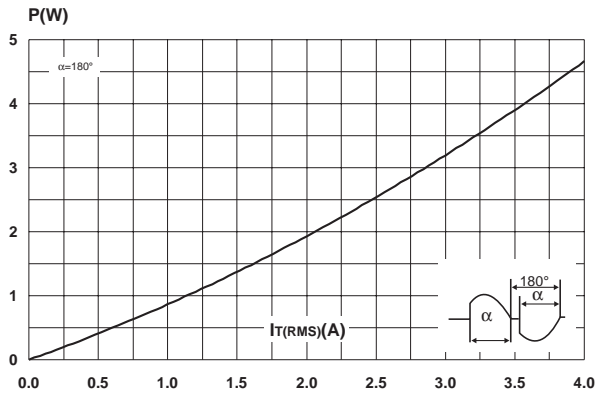


Fig. 2: RMS on-state current versus case temperature.

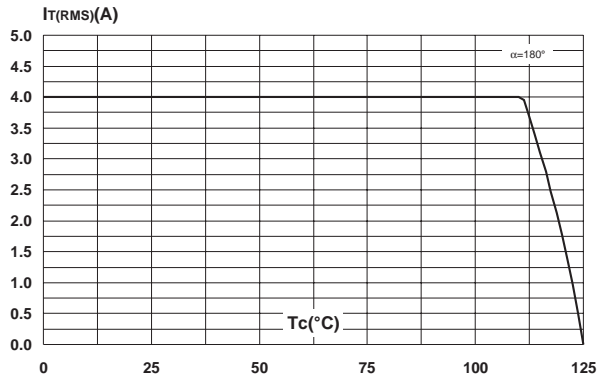


Fig. 3: Relative variation of thermal impedance versus pulse duration.

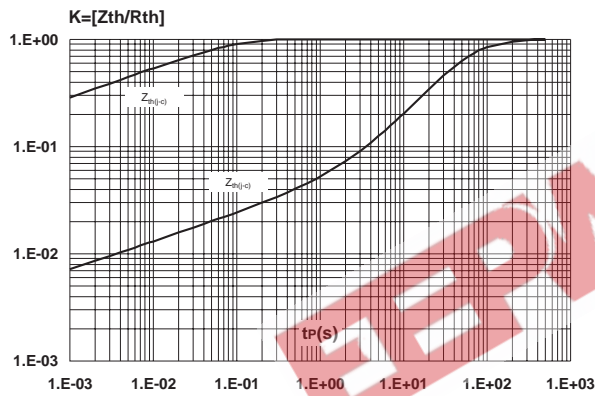


Fig. 4: On-state characteristics (maximum values).

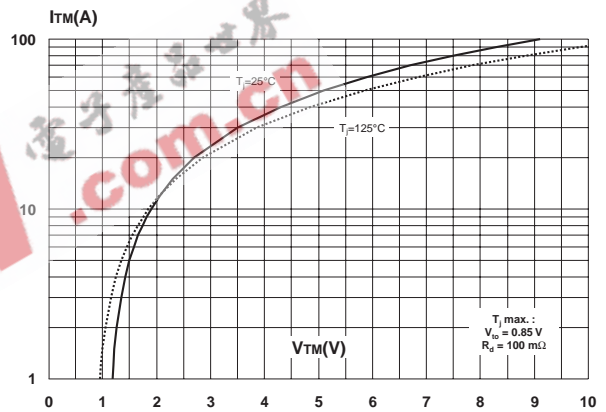


Fig. 5: Surge peak on-state current versus number of cycles.

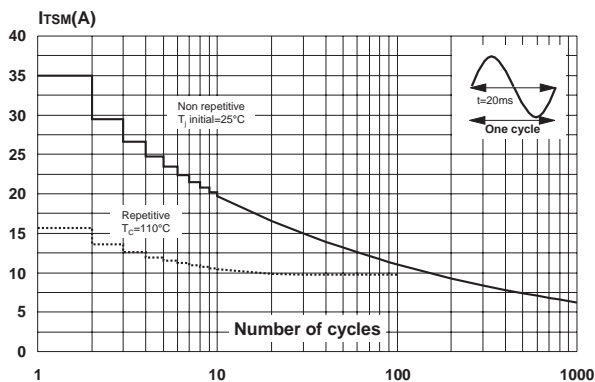


Fig. 6: Non repetitive surge peak on-state current for a sinusoidal pulse with width $t_p < 10\text{ms}$, and corresponding value of I^2t .

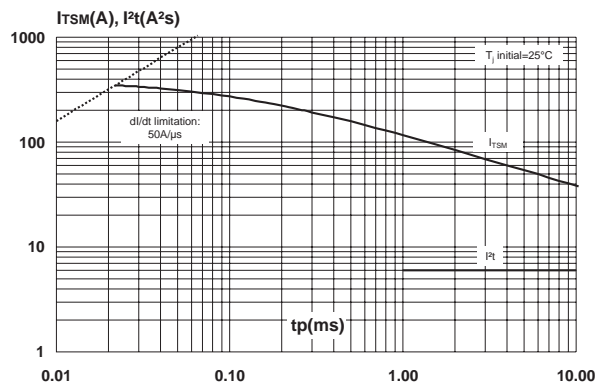


Fig. 7: Relative variation of gate trigger current, holding current and latching current versus junction temperature (typical values).

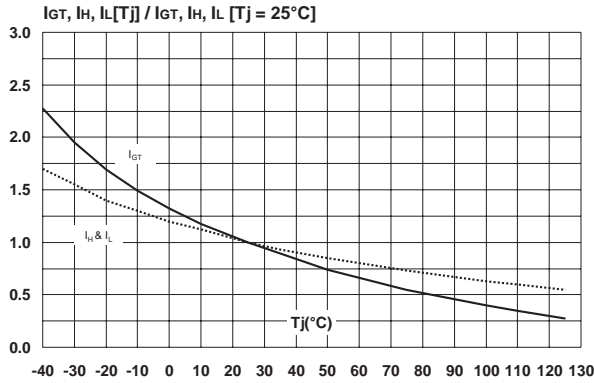


Fig. 8: Relative variation of critical rate of decrease of main current versus reapplied dV/dt (typical values).

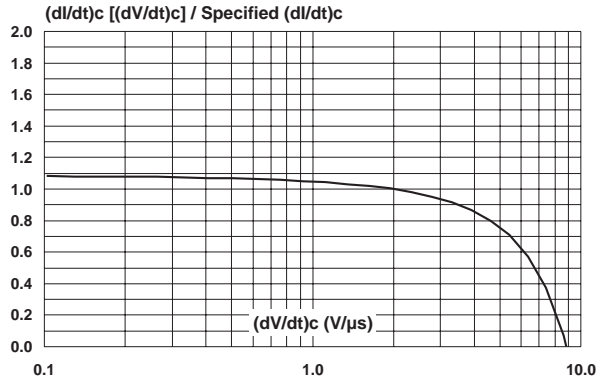


Fig. 9: Relative variation of critical rate of decrease of main current versus junction temperature.

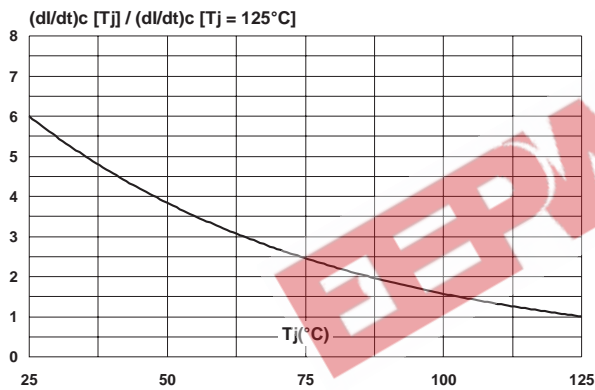


Fig. 10: Relative variation of static dV/dt immunity versus junction temperature.

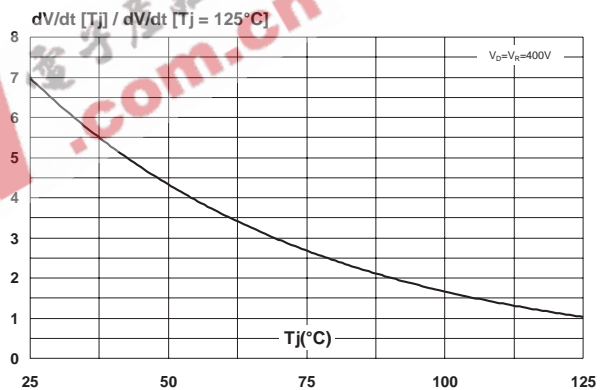
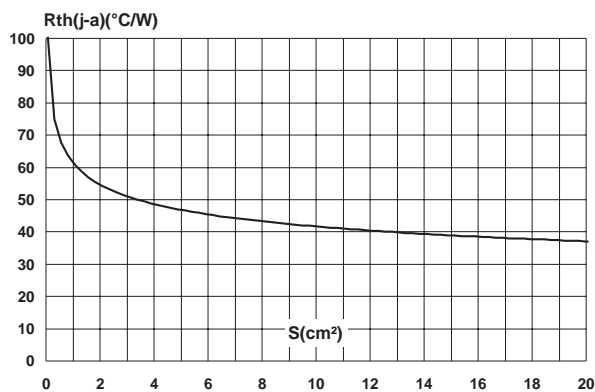
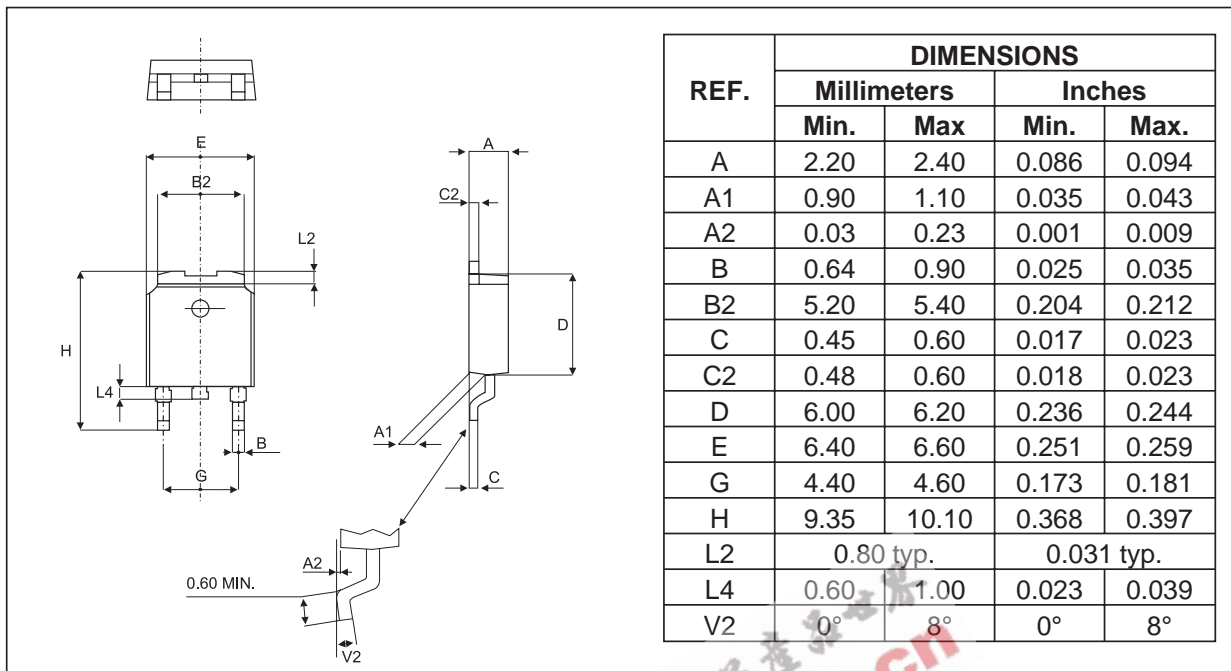


Fig. 11: Thermal resistance junction to ambient versus copper surface under tab (epoxy printed circuit board FR4, Cu = 35μm).

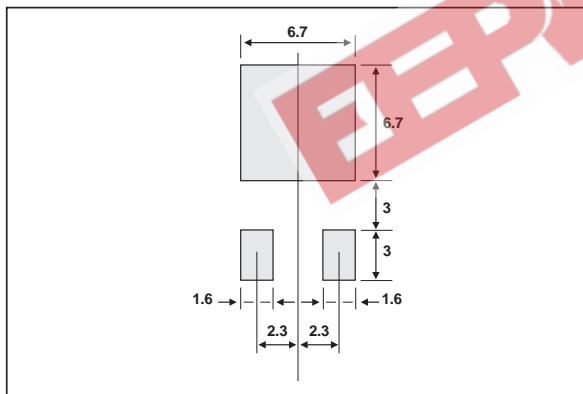


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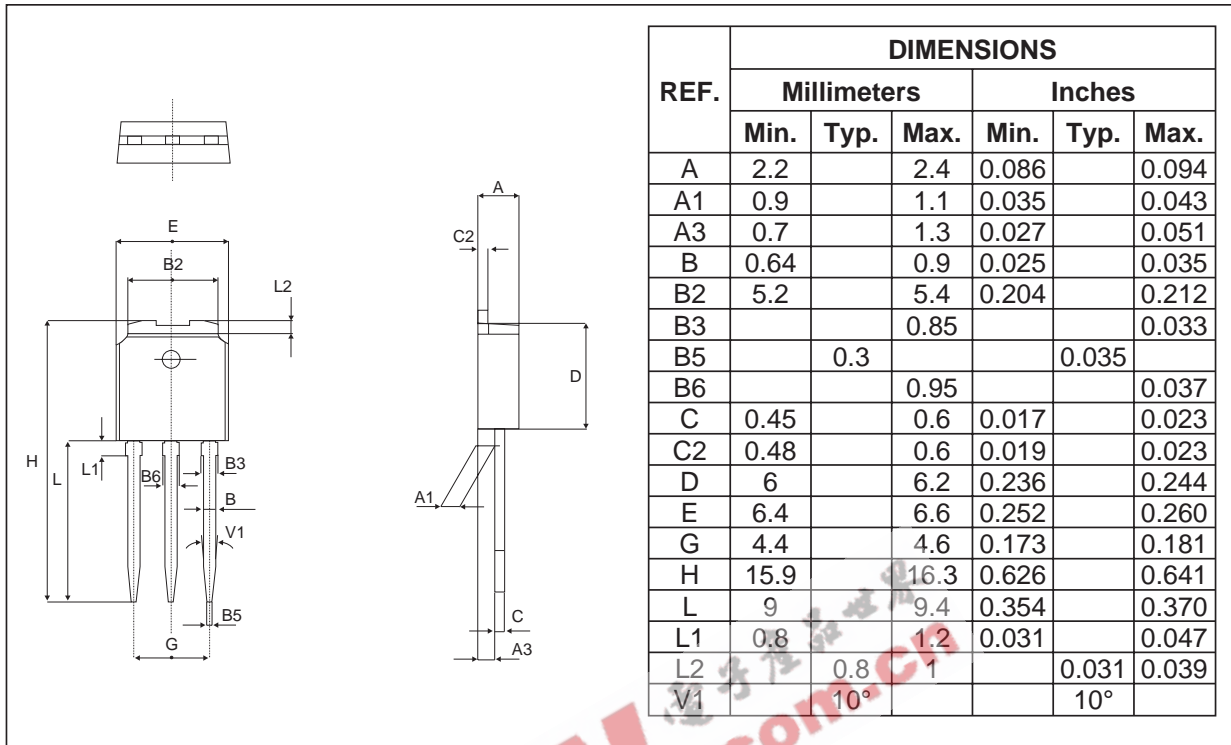
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